Gamma Irradiation of sLHC Prototype Silicon Strip Detectors and Test Structures of the SMART Collaboration

SCIPP, UC Santa Cruz, CA 95064 USA
M. Boscardin, C. Piemonte, A. Pozza, and N. Zorzi
ITC-irst, Divisione Microsistemi, Via Sommarive 18, I-38050 Povo (Trento), Italy
G.-F. Dalla Betta
DIT, Università di Trento, Via Sommarive 14, I-38050 Povo (Trento), Italy
M. Bruzzi
Dip. Energetica, Univ. of Florence
Via S. Marta 3, I-50139 Firenze, Italy
A. Macchiolo
INFN Florence
Via G. Sansone 1, I-50019 Sesto F., Italy
L. Borello, A. Messineo
INFN Pisa
Largo B. Pontecorvo, 3, I - 56127 Pisa, Italy
Donato Creanza
INFN Bari,
Via E. Orabona 4, I-70126 Bari, Italy

For the SMART Collaboration

For the future luminosity upgrade proposed for the Large Hadron Collider (LHC) silicon strip detectors (SSD) and test structures were fabricated on various high-resistivity substrates (p-type MCz and FZ, n-type FZ) within the INFN funded SMART project. They were irradiated with $^{60}$Co to test total dose (TID) effects, in order to study the impact of surface radiation damage on the detector properties (interstrip capacitance and resistance, break-down voltage). Selected results from the pre-rad and post-rad characterization of detectors and test structures will be presented at the conference, in particular interstrip capacitance, break-down voltage, flatband voltage and oxide charge.